

P25051

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : I. E. LUKÁCS et al.

Serial No. : Not Yet Assigned

Filed : Concurrently Herewith

For : APPARATUS AND MEASUREMENT PROCEDURE FOR THE FAST, QUANTITATIVE, NON-CONTACT TOPOGRAPHIC INVESTIGATION OF SEMICONDUCTOR WAFERS AND OTHER MIRROR LIKE SURFACES

CLAIM OF PRIORITY

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Applicant hereby claims the right of priority granted pursuant to 35 U.S.C. 119 based upon Hungarian application No. P0104057, filed 02 October 2001. As required by 37 C.F.R. 1.55, a certified copy of the Hungarian application has been filed in parent Application No. PCT/EP02/11011 filed October 01, 2002..

Respectfully submitted,
I. E. LUKÁCS et al.

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